FAIRCHILD

SEMICONDUCTOR®

FSAM30SH60A

SPM[™] (Smart Power Module)

General Description

FSAM30SH60A is an advanced smart power module (SPM) that Fairchild has newly developed and designed to provide very compact and high performance ac motor drives mainly targeting high speed low-power inverterdriven application like washing machines. It combines optimized circuit protection and drive matched to low-loss IGBTs. Highly effective short-circuit current detection/ protection is realized through the use of advanced current sensing IGBT chips that allow continuous monitoring of the IGBTs current. System reliability is further enhanced by the built-in over-temperature monitoring and integrated undervoltage lock-out protection. The high speed built-in HVIC provides opto-coupler-less IGBT gate driving capability that further reduce the overall size of the inverter system design. In addition the incorporated HVIC facilitates the use of single-supply drive topology enabling the FSAM30SH60A to be driven by only one drive supply voltage without negative bias. Inverter current sensing application can be achieved due to the divided negative dc terminals.

Features

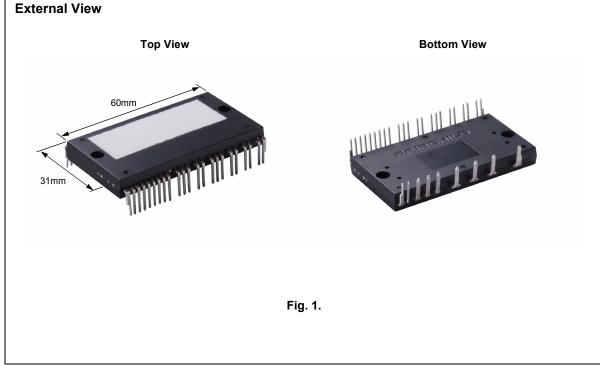
- UL Certified No. E209204
- 600V-30A 3-phase IGBT inverter bridge including control ICs for gate driving and protection

FSAM30SH60A

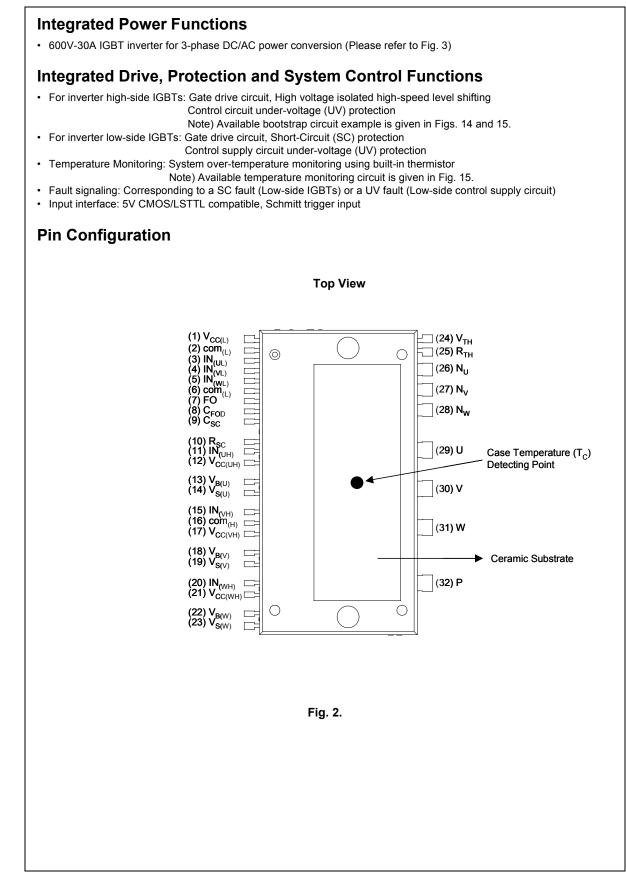
- Divided negative dc-link terminals for inverter current sensing applications
- · Single-grounded power supply due to built-in HVIC
- Typical switching frequency of 15kHz
- · Built-in thermistor for over-temperature monitoring
- Inverter power rating of 2.4kW / 100~253 Vac
- Isolation rating of 2500Vrms/min.
- Very low leakage current due to using ceramic substrate
- Adjustable current protection level by varying series resistor value with sense-IGBTs

Applications

- AC 100V ~ 253V 3-phase inverter drive for small power (2.4kW) ac motor drives
- Home appliances applications requiring high switching frequency operation like washing machines drive system
- Application ratings:
- Power : 2.4kW / 100~253 Vac
- Switching frequency : Typical 15kHz (PWM Control)
- 100% load current : 11A (Irms)
- 150% load current : 16.5A (Irms) for 1 minute



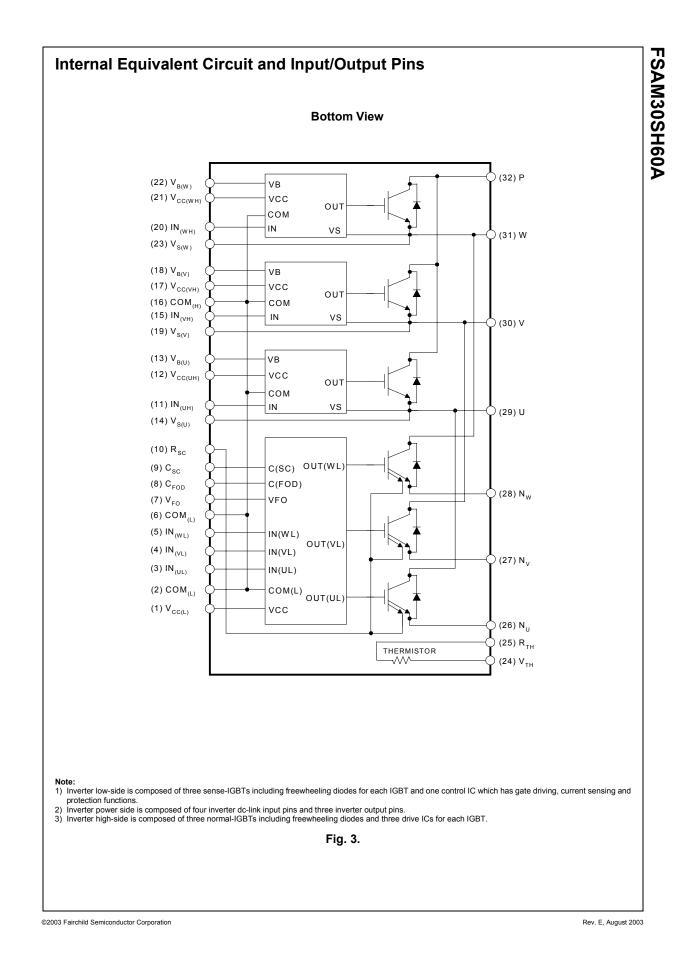




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19 V _{S(V)} High-side Bias Voltage Ground for V Phase IGBT Driving 20 IN _(WH) Signal Input for High-side W Phase
20 IN(WH) Signal Input for High-side W Phase
22 V _{B(W)} High-side Bias Voltage for W Phase IGBT Driving
23 V _{S(W)} High-side Bias Voltage Ground for W Phase IGBT Driving
25 R _{TH} Series Resistor for the Use of Thermistor (Temperature Detection) 26 N _U Negative DC–Link Input for U Phase
27 N _V Negative DC-Link Input for V Phase
28 N _W Negative DC-Link Input for W Phase 29 U Output for U Phase
30 V Output for V Phase
31 W Output for W Phase
32 P Positive DC–Link Input

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FSAM30SH60A



Absolute Maximum Ratings (T_J = 25°C, Unless Otherwise Specified)

Inverter Part

Item	Symbol	Condition	Rating	Unit	
Supply Voltage	V _{PN}	Applied between P- N_U , N_V , N_W	450	V	
Supply Voltage (Surge)	V _{PN(Surge)}	Applied between P- N_U , N_V , N_W	500	V	
Collector-Emitter Voltage	V _{CES}		600	V	
Each IGBT Collector Current	± I _C	$T_{\rm C} = 25^{\circ}{\rm C}$	30	A	
Each IGBT Collector Current	± I _C	T _C = 100°C	15	A	
Each IGBT Collector Current (Peak)	± I _{CP}	T _C = 25°C, Instantaneous Value (Pulse)	60	A	
Collector Dissipation	P _C	T _C = 25°C per One Chip	62	W	
Operating Junction Temperature	TJ	(Note 1)	-20 ~ 125	°C	

Note: 1. It would be recommended that the average junction temperature should be limited to $T_J \le 125^{\circ}C$ (@ $T_C \le 100^{\circ}C$) in order to guarantee safe operation.

Control Part

Item	Symbol	Condition	Rating	Unit
Control Supply Voltage	V _{CC}	Applied between $V_{CC(UH)}$, $V_{CC(VH)}$, $V_{CC(WH)}$ - $COM_{(H)}$, $V_{CC(L)}$ - $COM_{(L)}$	20	V
High-side Control Bias Voltage	V _{BS}	Applied between $V_{B(U)}$ - $V_{S(U)},V_{B(V)}$ - $V_{S(V)},V_{B(W)}$ - $V_{S(W)}$	20	V
Input Signal Voltage	V _{IN}	$ \begin{array}{l} \mbox{Applied between IN}_{(UH)}, \mbox{IN}_{(VH)}, \mbox{IN}_{(WH)} \mbox{-} \mbox{COM}_{(H)} \\ \mbox{IN}_{(UL)}, \mbox{IN}_{(VL)}, \mbox{IN}_{(WL)} \mbox{-} \mbox{COM}_{(L)} \end{array} $	-0.3 ~ V _{CC} +0.3	V
Fault Output Supply Voltage	V _{FO}	Applied between V _{FO} - COM _(L)	-0.3 ~ V _{CC} +0.3	V
Fault Output Current	I _{FO}	Sink Current at V _{FO} Pin	5	mA
Current Sensing Input Voltage	V _{SC}	Applied between C _{SC} - COM _(L)	$-0.3 \sim V_{CC} + 0.3$	V

Total System

Item	Symbol	Condition	Rating	Unit
Self Protection Supply Voltage Limit (Short-Circuit Protection Capability)	V _{PN(PROT)}	$V_{CC} = V_{BS} = 13.5 \sim 16.5V$ T _J = 25°C, Non-repetitive, less than 6µs	400	V
Module Case Operation Temperature	T _C	Note Fig.2	-20 ~ 100	°C
Storage Temperature	T _{STG}		-20 ~ 125	°C
Isolation Voltage	V _{ISO}	60Hz, Sinusoidal, AC 1 minute, Connection Pins to Heat-sink Plate	2500	V _{rms}

Absolute Maximum Ratings

Thermal Resistance

Item	Symbol	Condition	Min.	Тур.	Max.	Unit
Junction to Case Thermal Resistance	R _{th(j-c)Q}	Each IGBT under Inverter Operating Condition		-	2.0	°C/W
	R _{th(j-c)F}	Each FWDi under Inverter Operating Condition	-	-	3.2	°C/W
Contact Thermal Resistance	R _{th(c-f)}	Ceramic Substrate (per 1 Module) Thermal Grease Applied (Note 3)	-	-	0.06	°C/W

 $\begin{array}{l} \textbf{Note:}\\ \textbf{2. For the measurement point of case temperature(T_C), please refer to Fig. 2.\\ \textbf{3. The thickness of thermal grease should not be more than 100um.} \end{array}$

Electrical Characteristics (T_J = 25°C, Unless Otherwise Specified)

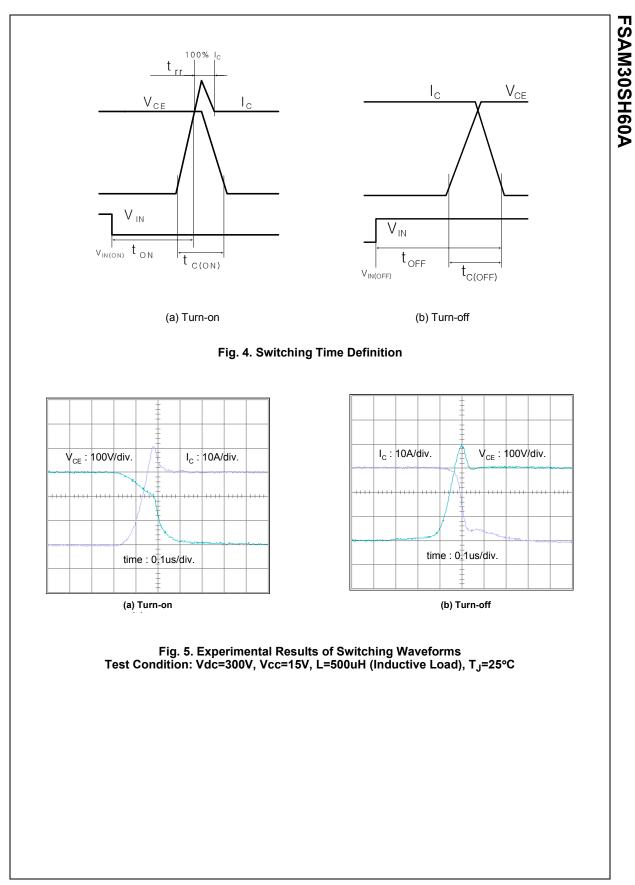
Inverter Part

Item	Symbol	Conditi	on	Min.	Тур.	Max.	Unit
Collector - Emitter Saturation Voltage	V _{CE(SAT)}	$V_{CC} = V_{BS} = 15V$ $V_{IN} = 0V$	I _C = 30A, T _J = 25°C	-	-	2.5	V
FWDi Forward Voltage	V _{FM}	V _{IN} = 5V	I _C = 30A, T _J = 25°C	-	-	2.6	V
Switching Times	t _{ON}	V _{PN} = 300V, V _{CC} = V _{BS} = 15	-	0.39	-	us	
	t _{C(ON)}	$I_{\rm C} = 30$ A, $T_{\rm J} = 25^{\circ}$ C			0.2	-	us
	t _{OFF}	$V_{IN} = 5V \leftrightarrow 0V$, Inductive Load (High, Low-side)		-	0.85	-	us
	t _{C(OFF)}	(Fight, Low-side)		-	0.24	-	us
	t _{rr}	(Note 4)		-	0.13	-	us
Collector - Emitter Leakage Current	I _{CES}	$V_{CE} = V_{CES}, T_J = 25^{\circ}C$		-	-	250	μA

Note:

4. t_{ON} and t_{OFF} include the propagation delay time of the internal drive IC. $t_{C(ON)}$ and $t_{C(OFF)}$ are the switching time of IGBT itself under the given gate driving condition internally. For the detailed information, please see Fig. 4.

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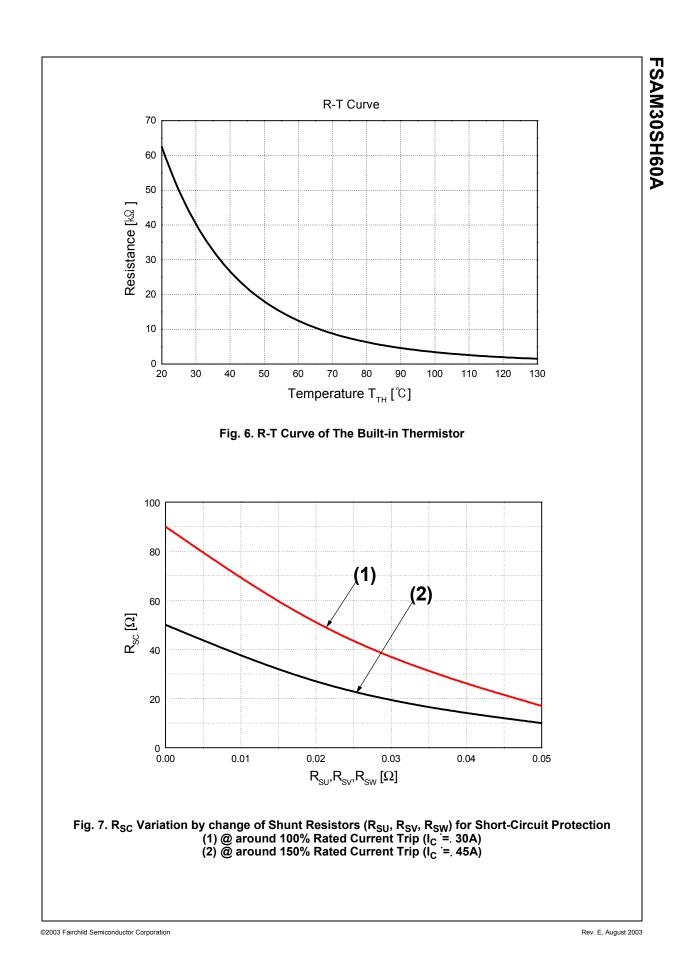
Item	Symbol		Condition	Min.	Тур.	Max.	Unit
Quiescent V_{CC} Supply Current	IQCCL	V _{CC} = 15V IN _(UL, VL, WL) = 5V	V _{CC(L)} - COM _(L)	-	-	26	mA
	I _{QCCH}	V _{CC} = 15V IN _(UH, VH, WH) = 5V	V _{CC(UH)} , V _{CC(VH)} , V _{CC(WH)} - COM _(H)	-	-	130	uA
Quiescent V _{BS} Supply Cur- rent	I _{QBS}	V _{BS} = 15V IN _(UH, VH, WH) = 5V	$V_{B(U)} - V_{S(U)}, V_{B(V)} - V_{S(V)}, V_{B(W)} - V_{S(W)}$	-	-	420	uA
Fault Output Voltage	V _{FOH}	$V_{SC} = 0V, V_{FO}$ Circuit: 4.7k Ω to 5V Pull-up		4.5	-	-	V
	V _{FOL}	V_{SC} = 1V, V_{FO} Circuit: 4.7k Ω to 5V Pull-up		-	-	1.1	V
Short-Circuit Trip Level	V _{SC(ref)}	V _{CC} = 15V (Note 5)			0.51	0.56	V
Sensing Voltage of IGBT Current	V _{SEN}	R _{SC} = 50 Ω, R _{SU} = F (Note Fig. 7)	0.45	0.51	0.56	V	
Supply Circuit Under-	UV _{CCD}	Detection Level		11.5	12	12.5	V
Voltage Protection	UV _{CCR}	Reset Level Detection Level		12	12.5	13	V
	UV _{BSD}			7.3	9.0	10.8	V
	UV _{BSR}	Reset Level		8.6	10.3	12	V
Fault Output Pulse Width	t _{FOD}	C _{FOD} = 33nF (Note 6)	1.4	1.8	2.0	ms
ON Threshold Voltage	V _{IN(ON)}	High-Side	Applied between IN _(UH) , IN _(VH) ,	-	-	0.8	V
OFF Threshold Voltage	V _{IN(OFF)}		IN _(WH) - COM _(H)	3.0	-	-	V
ON Threshold Voltage	V _{IN(ON)}	Low-Side	Applied between IN _(UL) , IN _(VL) ,	-	-	0.8	V
OFF Threshold Voltage	V _{IN(OFF)}	1	IN _(WL) - COM _(L)	3.0	-	-	V
Resistance of Thermistor	R _{TH}	@ T _{TH} = 25°C (Note	Fig. 6) (Note 7)	-	50	-	kΩ
		@ T _{TH} = 100°C (Note	e Fig. 6) (Note 7)	-	3.4	-	kΩ

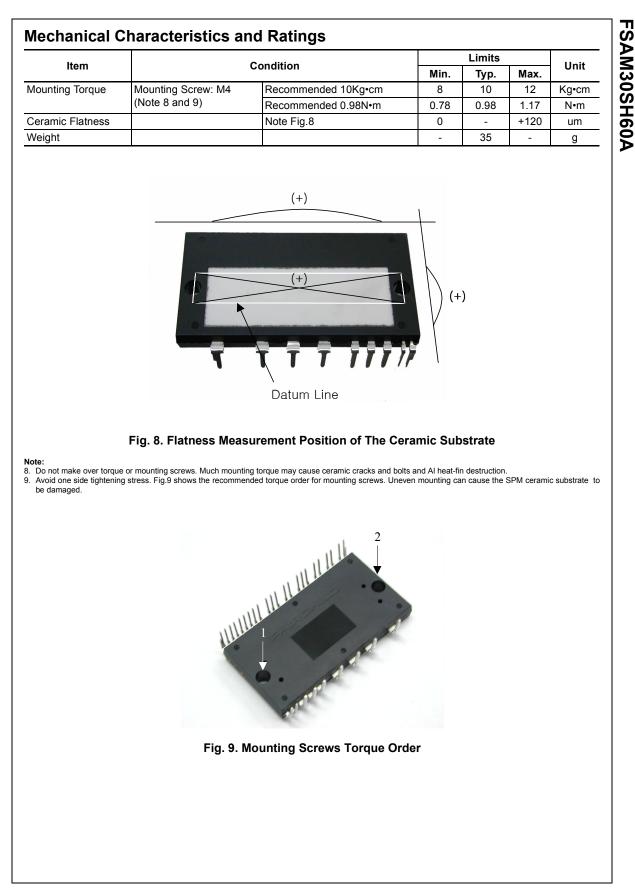
Electrical Characteristics (T_J = 25°C, Unless Otherwise Specified)

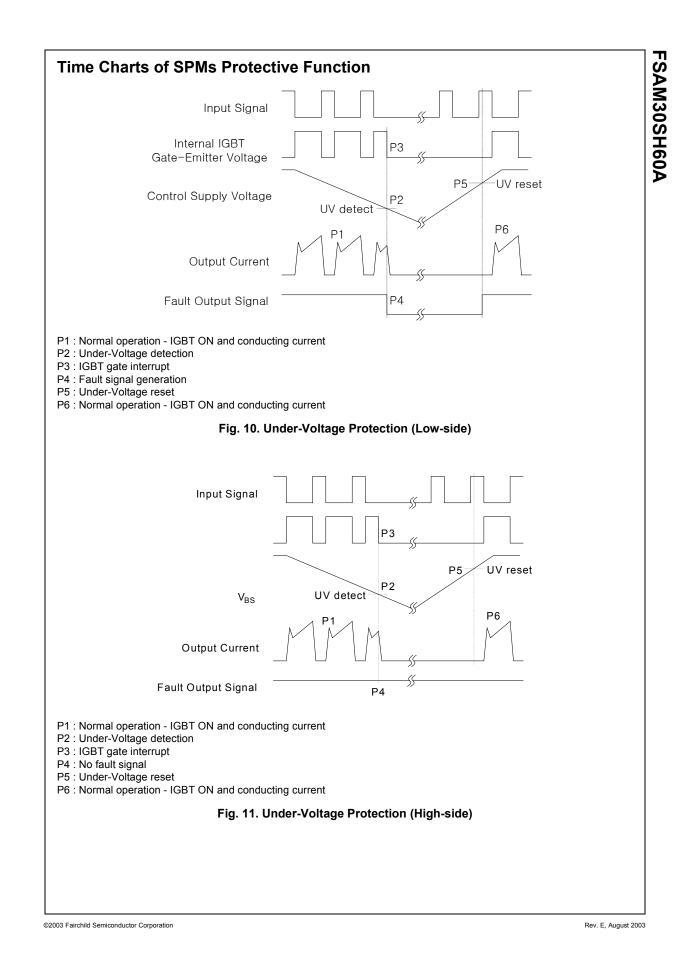
Note:
5. Short-circuit current protection is functioning only at the low-sides. It would be recommended that the value of the external sensing resistor (R_{SC}) should be selected around 50 Ω in order to make the SC trip-level of about 45A at the shunt resistors (R_{SU}, R_{SV}, R_{SW}) of 0Ω. For the detailed information about the relationship between the external sensing resistor (R_{SC}) and the shunt resistors (R_{SU}, R_{SV}, R_{SW}), please see Fig. 7.
6. The fault-out pulse width t_{FOD} depends on the capacitance value of C_{FOD} according to the following approximate equation : C_{FOD} = 18.3 x 10⁻⁶ x t_{FOD}[F]
7. T_{TH} is the temperature of thermistor itself. To know case temperature (T_C), please make the experiment considering your application.

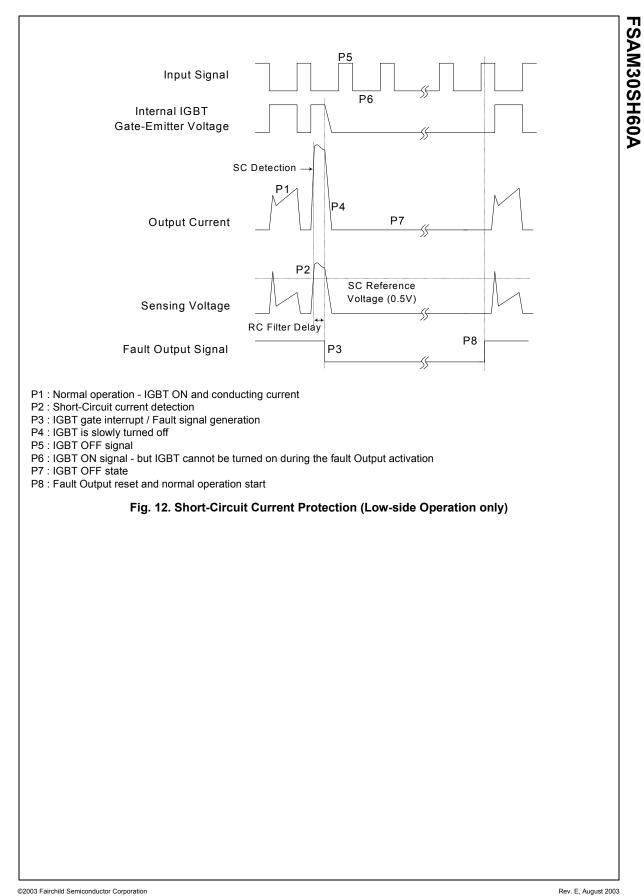
Recommended Operating Conditions

	Quanta	Condition		Values		
Item	Symbol	Condition	Min.	Тур.	Max.	Unit
Supply Voltage	V _{PN}	Applied between P - N _U , N _V , N _W	-	300	400	V
Control Supply Voltage	V _{CC}	Applied between $V_{CC(UH), V_{CC(VH), V_{CC(WH)}}$ - COM _(H) , $V_{CC(L)}$ - COM _(L)		15	16.5	V
High-side Bias Voltage	V _{BS}	Applied between $V_{B(U)}$ - $V_{S(U)}$, $V_{B(V)}$ - $V_{S(V)}$, $V_{B(W)}$ - $V_{S(W)}$	13.5	15	16.5	V
Blanking Time for Preventing Arm-short	t _{dead}	For Each Input Signal	3	-	-	us
PWM Input Signal	f _{PWM}	T _C ≤ 100°C, T _J ≤ 125°C	-	15	-	kHz
Input ON Threshold Voltage	V _{IN(ON)}	$\begin{array}{l} \mbox{Applied between IN}_{(UH)}, \mbox{ IN}_{(VH)}, \mbox{ IN}_{(WH)} - \\ \mbox{COM}_{(H)}, \mbox{ IN}_{(UL)}, \mbox{ IN}_{(VL)}, \mbox{ IN}_{(WL)} - \mbox{COM}_{(L)} \end{array}$		0~0.65	5	V
Input OFF Threshold Voltage	V _{IN(OFF)}	$\begin{array}{l} \text{Applied between IN}_{(\text{UH})}, \text{IN}_{(\text{VH})}, \text{IN}_{(\text{WH})} \text{ - } \\ \text{COM}_{(\text{H})}, \text{IN}_{(\text{UL})}, \text{IN}_{(\text{VL})}, \text{IN}_{(\text{WL})} \text{ - } \text{COM}_{(\text{L})} \end{array}$		4~5.5		V

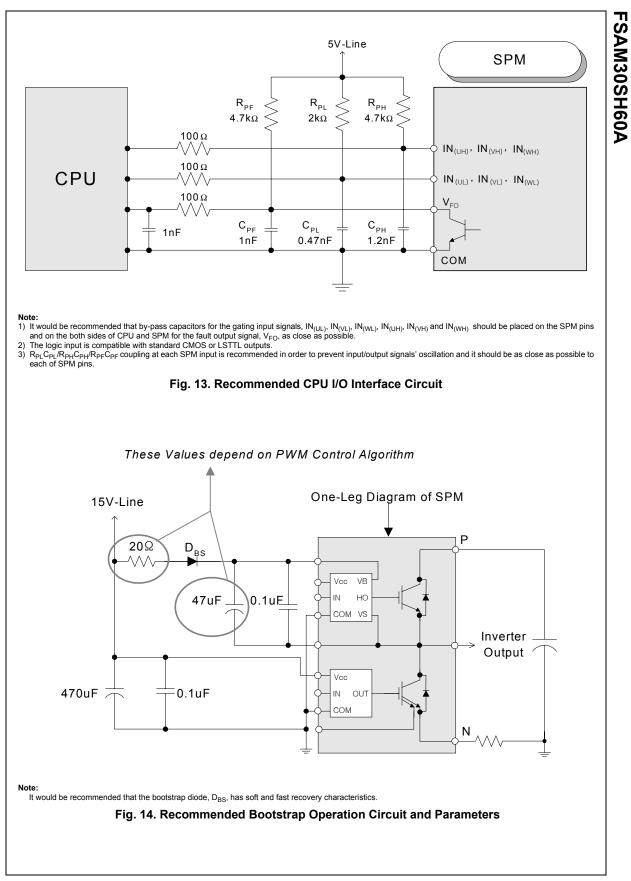


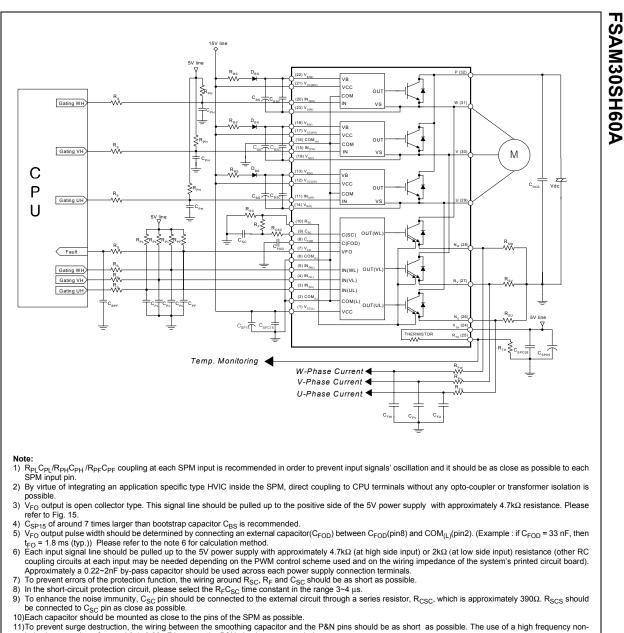






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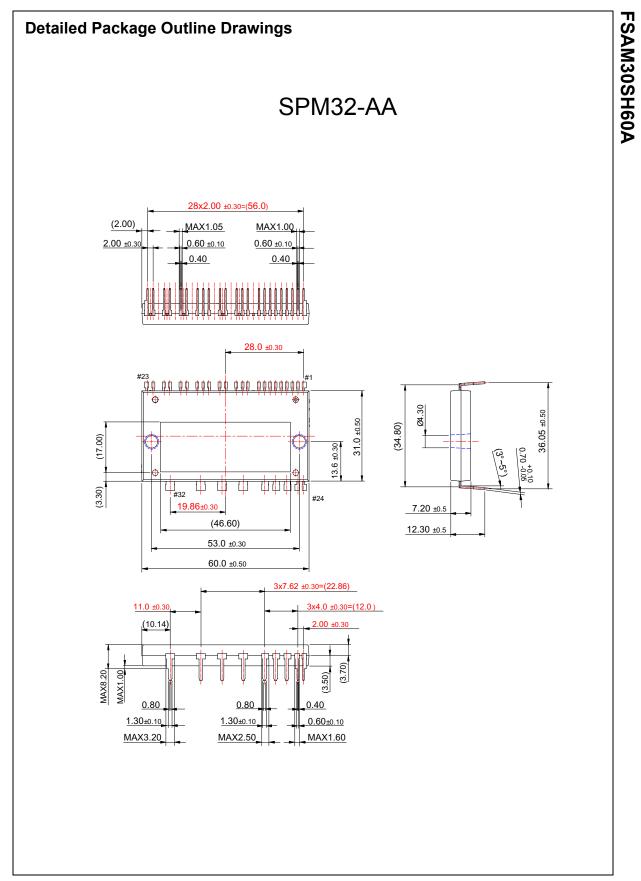




inductive capacitor of around 0.1~0.22 uF between the P&N pins is recommended.

12)Relays are used at almost every systems of electrical equipments of home appliances. In these cases, there should be sufficient distance between the CPU and the relays. It is recommended that the distance be 5cm at least.

Fig. 15. Typical Application Circuit



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CROSSVOLT™	GlobalOptoisolator™	MICROWIRE™	QT Optoelectronics [™]	TINYOPTO™
DOME™	GTO™່	MSX™	Quiet Series [™]	TruTranslation™
EcoSPARK™	HiSeC™	MSXPro™	RapidConfigure™	UHC™
E ² CMOS [™]	I²C™	OCX™	RapidConnect™	UltraFET [®]
EnSigna™	ImpliedDisconnect™	OCXPro™	SILENT SWITCHER®	VCX™
FACT™	ISOPLANAR™	OPTOLOGIC[®]	SMART START™	
Across the boar	d. Around the world.™	OPTOPLANAR™	SPM™	
The Power Fran		PACMAN™	Stealth™	
Programmable A		POP™	SuperSOT™-3	

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PRODUCT STATUS DEFINITIONS

Definition of Terms

Product Status	Definition
Formative or In Design	This datasheet contains the design specifications for product development. Specifications may change in any manner without notice.
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